Positron annihilation lifetime measurements of stainless steels irradiated in the SINQ target irradiation program

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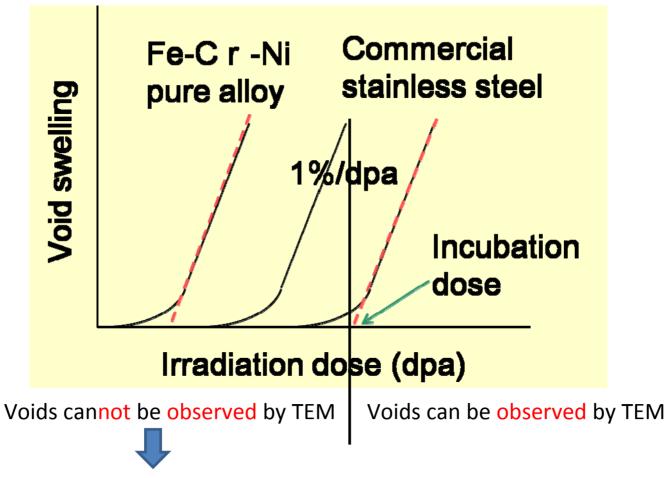
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Background

- Facilities with high irradiation dose are required.
 - Fast breeder reactor
 - Spallation neutron source / Accelerator driven system
 - Fusion reactor etc.
- Reduced activated ferritic/martensitic steel and austenitic stainless steels are candidates for the structural materials of the facilities.
- For development of irradiation-resistant materials, point defect processes in the incubation period of void formation is very important.

Void swelling of stainless steel



Positron annihilation spectroscopy is very powerful tool to detect vacancy type defects.

Purpose of this study

 Defect structures in reduced activated ferritic/martensitic steel F82H and austenitic stainless steel JPCA (Ti-added modified 316SS) during the incubation period were investigated after proton irradiation using positron annihilation lifetime measurement.

Experimental procedure

- Sample: F82H, JPCA (Ti-added modified 316SS)
- Irradiation condition (STIP-1)

F82H
Tensile test
sample

ID	Temp (℃)	dpa	He (appm)	H (appm)		
2-ST-L11-L	98	5.9	413	1680		
2-ST-L12-L	98					
2-ST-L11-H	124	8.5	650	2530		
2-ST-L12-H						
2-ST-L13-L	133	9.2	715	2850		
2-ST-L14-L						
2-ST-L13-H	175	12.3	1015	4200		
2-ST-L14-H						
2-ST-L15-H	240	17.2	1505	6200		
2-ST-L16-H						
2-ST-L17-H	207	20.4	1795	7720		
2-ST-L18-H	287					

Red: isochronal annealing (200, 300, 400, 600°C)

JPCA
Fatigue test
sample

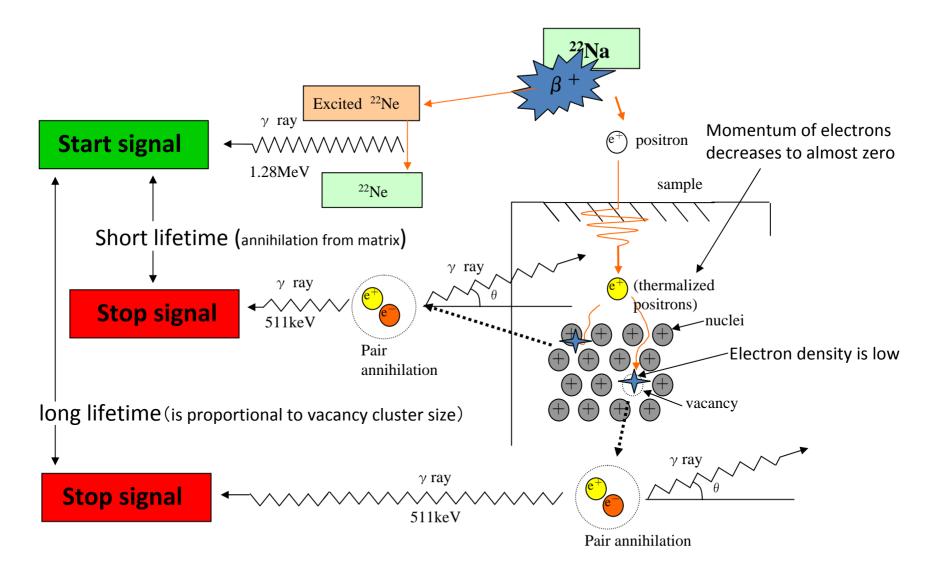
ID	Temp (℃)	dpa	He (appm)	H (appm)
F21	140	6.3		

isochronal annealing (every 100°C from 150°C to 1050°C)

Positron annihilation lifetime measurement



Positron annihilation lifetime measurement



Calculated positron annihilation lifetime

Table 1
The calculated positron lifetimes and binding energies for vacancy clusters in Ni, Cu, and Fe as a function of the cluster size

Ni			Cu			Fe		
Defect	τ (ps)	E _b (eV)	Defect	τ (ps)	E _b (eV)	Defect	τ (ps)	$E_{\rm b}~({\rm eV})$
Bulk	100	0.00	Bulk	110	0.00	Bulk	104	0.00
\mathbf{V}_1	169	3.34	\mathbf{V}_1	173	2.35	\mathbf{V}_1	180	3.56
V_2	188	3.82	V_2	196	2.74	V_2^a	187/202	3.86/4.11
V_4	246	4.66	V_4	255	3.36	V_5	246	4.89
V_7	265	4.92	V_7	274	3.57	V_9	280	5.32
V_{13}	341	5.54	V_{13}	348	4.07	V_{15}	368	6.01
V_{19}	371	5.77	V_{19}	377	4.28	V_{27}	396	6.27
V_{43}	410	6.15	V_{43}	413	4.62	V_{51}	419	6.55
V ₅₅	420	6.28	V_{55}	421	4.74	V_{59}	426	6.69
V_{79}	427	6.42	V ₇₉	428	4.86	V_{65}	427	6.72
V ₁₇₇	435	6.60	V_{177}	436	5.02	V_{137}	435	6.91

^a The values are listed for two distinct divacancy geometries, i.e. V₂ along [111] and [100] directions.

[H. Ohkubo et al., Mater. Sci. Eng. A350 (2003) 95.]

- Positron lifetime is proportional to the size of vacancy clusters.
- •In metallic system, Positron lifetime is less than 500ps.
 500ps is saturation value of positron lifetime.
 Even if void grows and is observed by TEM, positron lifetime of the void is less than 500ps.

Positron lifetime of vacancy clusters-He complexes in Fe

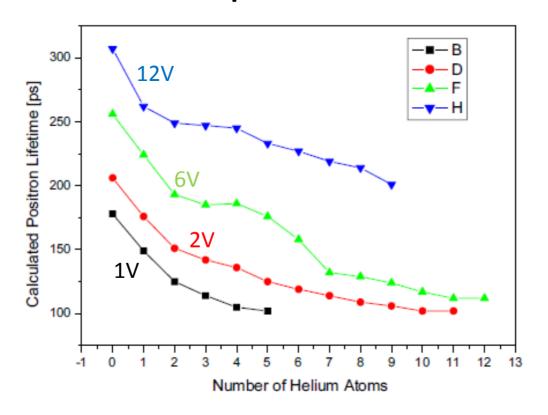
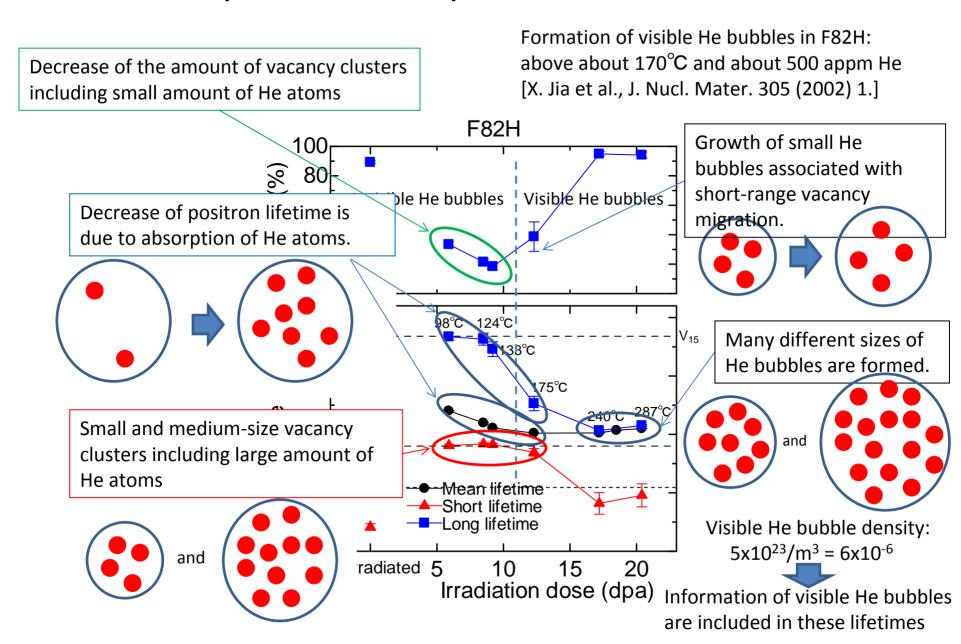


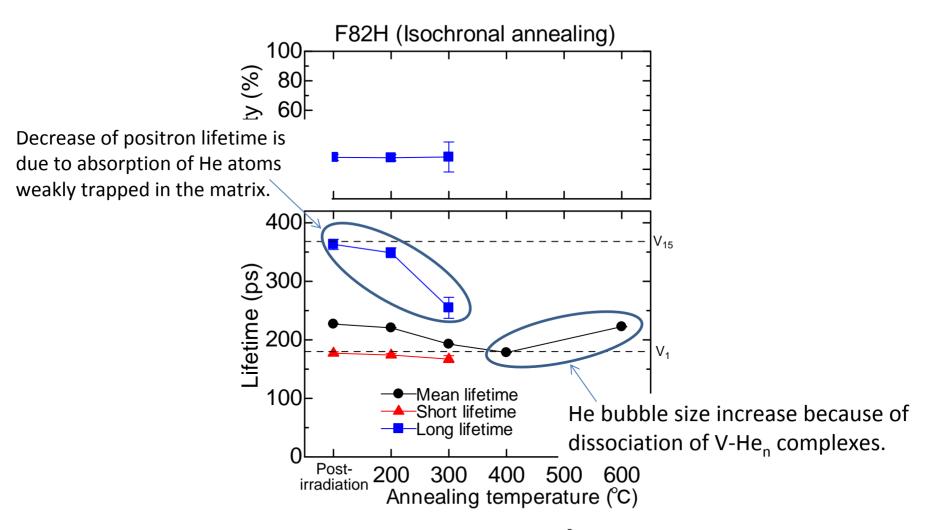
Figure 4 Correlation between positron lifetime and the number of helium atoms in nano-void (B) 1V+nHe, (D) 2V+nHe, (F) 6V+nHe, (H) 12V+nHe.

[T. Troev et al., Phys. Status Solidi C 6 (2009) 2373]

Dose dependence of positron lifetime in F82H

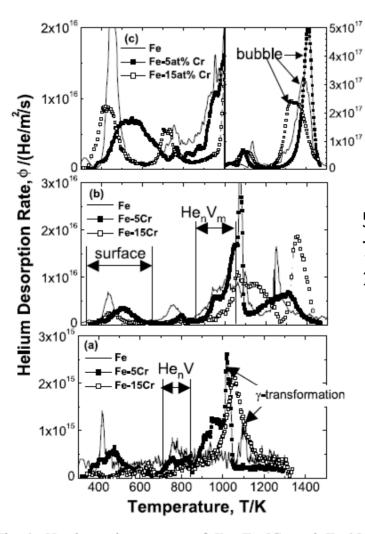


Annealing behavior of F82H



500°C: V-He_n complexes dissociate 700°C: V_m-He_n complexes dissociate 1100°C: Large He bubbles dissociate

TDS measurements of Fe-Cr alloys

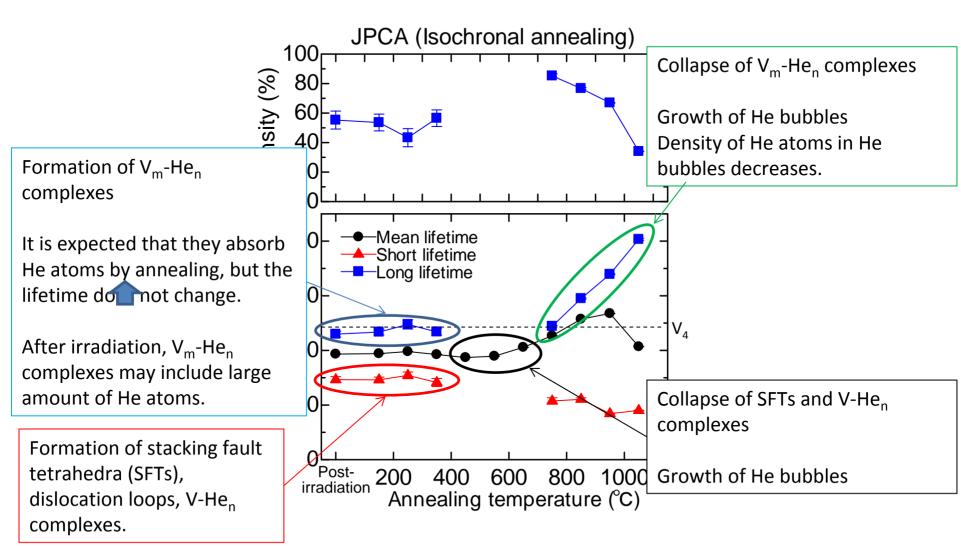


500°C: V-He_n complexes dissociate 700°C: V_m-He_n complexes dissociate 1100°C: Large He bubbles dissociate

Fig. 1. He desorption spectra of Fe, Fe–5Cr and Fe–15Cr irradiated by 8 keV He+ ions at room temperature. The irradiation doses are (a) 1017, (b) 1018 and (c) 10^{19} He⁺/m².

[R. Sugano et al., J.Nucl. Mater. 329–333 (2004) 942]

Annealing behavior of JPCA

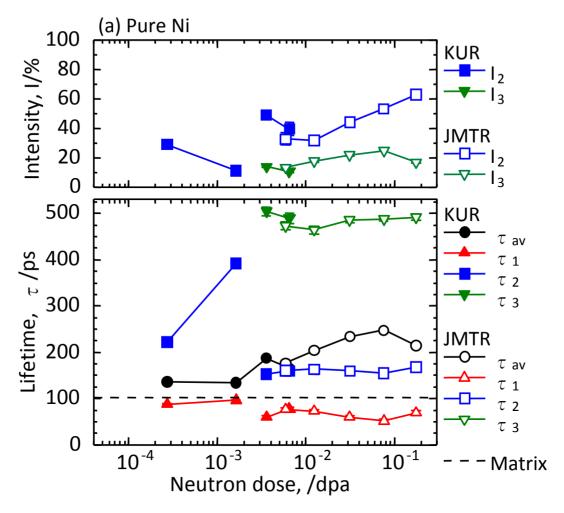


500°C: V-He_n complexes dissociate 700°C: V_m-He_n complexes dissociate 1100°C: Large He bubbles dissociate

Conclusion

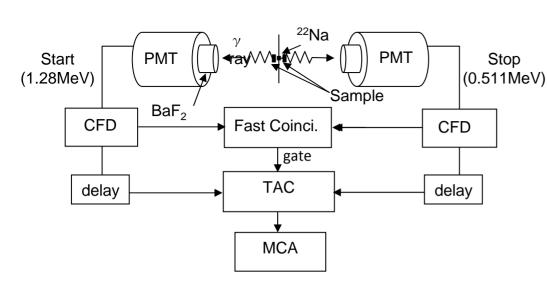
- Positron annihilation lifetime (PAL) measurements of F82H and JPCA irradiated with protons at SINQ were performed.
- We could detect the small vacancy clusters by PAL, which cannot be observed by TEM.
- In F82H, positron annihilation lifetime of He bubbles decreases with increasing the irradiation dose. Because the He bubbles absorb more He atoms.
- In isochronal annealing, we can detect the growth process of He bubbles.
- This is the first detection of small vacancy clusters and He bubbles in F82H and JPCA irradiated in the STIP.

Positron annihilation lifetimes in fission neutron-irradiated Ni

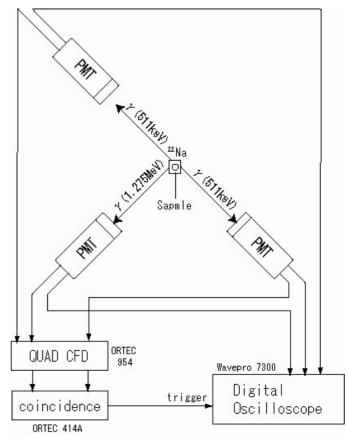


Void growth is observed by TEM in more than 0.01dpa, but positron lifetime is saturated.

Positron annihilation lifetime measurement system



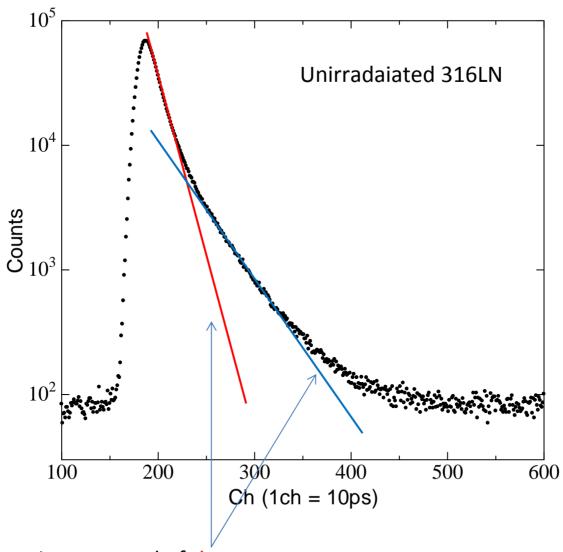
Conventional measurement system (two-detector system)



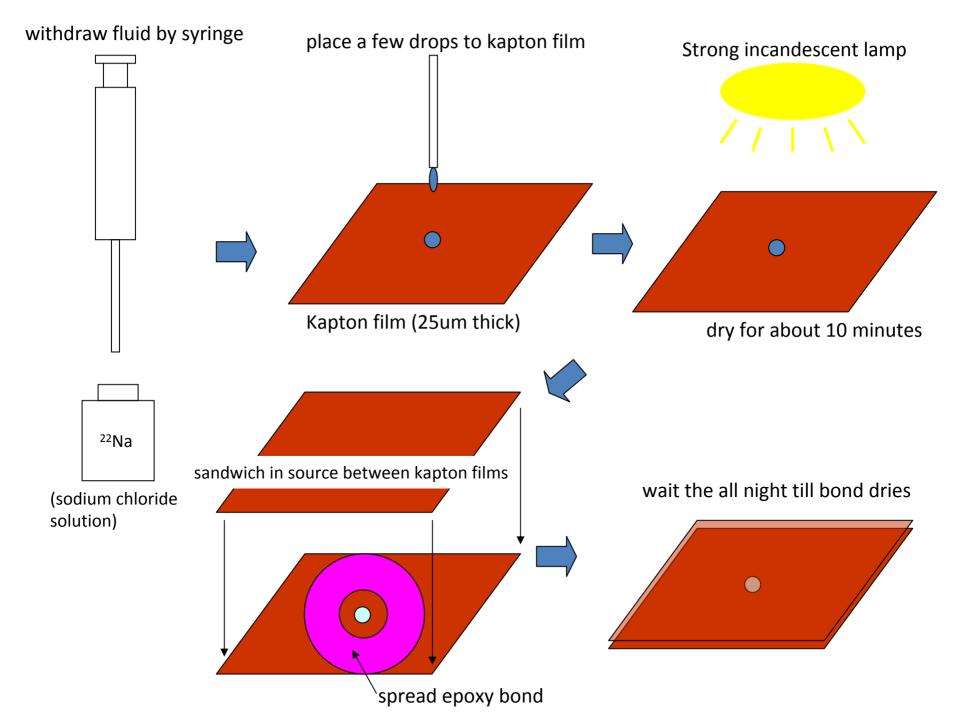
Improved measurement system using a digital oscilloscope (three-detector system)

Merit: Reduction of background Demerit: Decrease of count rate

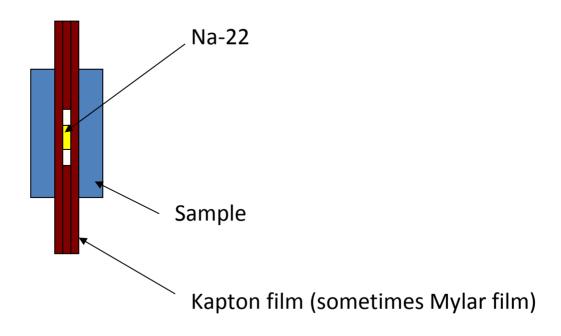
Positron annihilation lifetime spectrum



This spectrum is composed of these two curves.



Set of samples

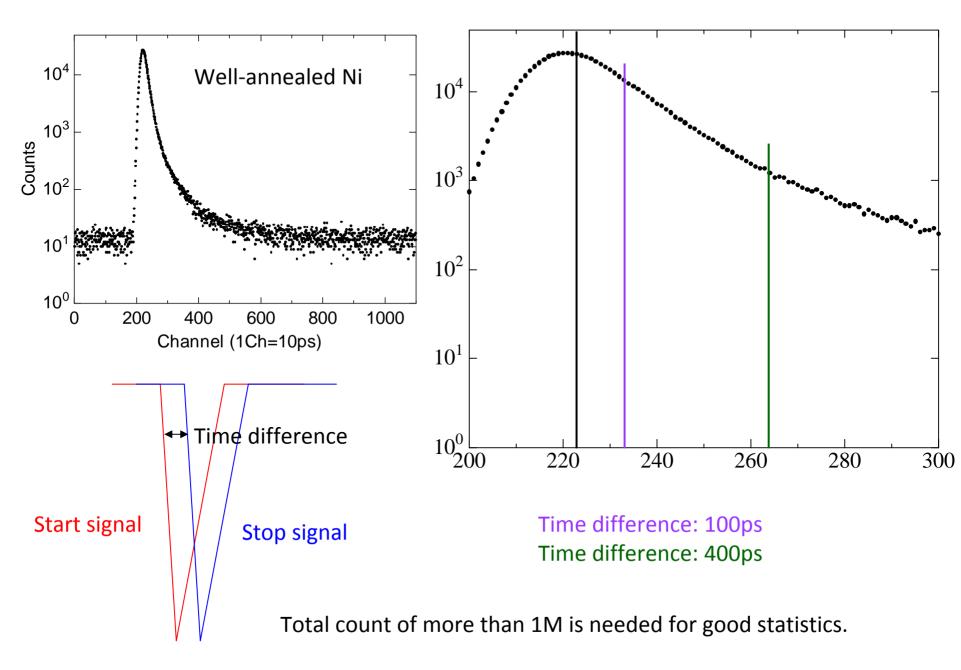


A part of positrons annihilate in the Kapton film.

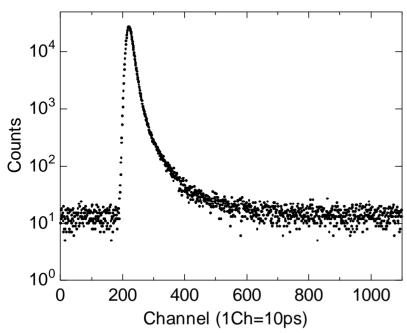
Ratio of positrons, which annihilate at Kapton film, depends on the thickness.

5um: ~13%, 10um: ~20%, 25um: ~33%

How to make lifetime spectrum



Analysis of lifetime spectrum



 $T'(t) = \int_{-\infty}^{\infty} T(x)G(t-x)dx + B$ $\int_{-\infty}^{\infty} G(t)dt = 1$

T': Lifetime spectrum (left figure)

which is developed by one group of Riso DTU.

T: Decay function

G: Time-resolution function

We usually use PALSfit program,

B: Background

One component

$$T(t) = \frac{I_1}{\tau_1} \exp\left(-\frac{t}{\tau_1}\right)$$

G is given by a sum of two or three Gaussians

Two components

$$T(t) = \frac{I_1}{\tau_1} \exp\left(-\frac{t}{\tau_1}\right) + \frac{I_2}{\tau_2} \exp\left(-\frac{t}{\tau_2}\right)$$

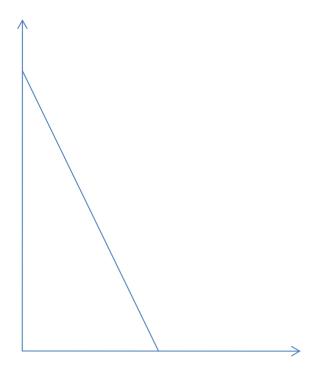
 τ : lifetime

I : lifetime intensity

Three components

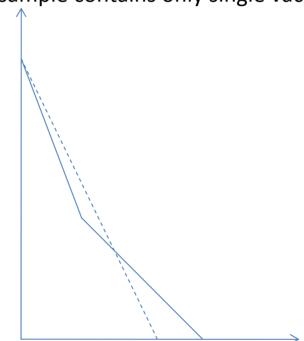
$$T(t) = \frac{I_1}{\tau_1} \exp\left(-\frac{t}{\tau_1}\right) + \frac{I_2}{\tau_2} \exp\left(-\frac{t}{\tau_2}\right) + \frac{I_3}{\tau_3} \exp\left(-\frac{t}{\tau_3}\right)$$

Without any defects



$$\tau = \frac{1}{\lambda_m} \approx 100 \, ps$$

With single vacancies (sample contains only single vacancies)



$$\tau_1 = \frac{1}{\lambda_m + \kappa} < 100 \, ps$$

$$\tau_2 = \frac{1}{\lambda_d} \approx 170 - 500 \, ps$$

 λ_m : positron annihilation rate in the matrix

 λ_d : positron annihilation rate at the defect site

 κ : positron transition rate from the matrix to the defect site